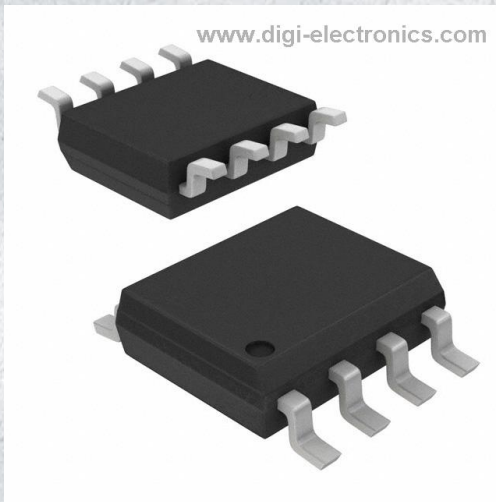


FDS8934A Datasheet



<https://www.DiGi-Electronics.com>

DiGi Electronics Part Number	FDS8934A-DG
Manufacturer	onsemi
Manufacturer Product Number	FDS8934A
Description	MOSFET 2P-CH 20V 4A 8SOIC
Detailed Description	Mosfet Array 20V 4A 900mW Surface Mount 8-SOIC



Tel: +00 852-30501935

RFQ Email: Info@DiGi-Electronics.com

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Purchase and inquiry

Manufacturer Product Number:

FDS8934A

Series:

-

Technology:

MOSFET (Metal Oxide)

FET Feature:

Logic Level Gate

Current - Continuous Drain (Id) @ 25°C:

4A

Vgs(th) (Max) @ Id:

1V @ 250µA

Input Capacitance (Ciss) (Max) @ Vds:

1130pF @ 10V

Operating Temperature:

-55°C ~ 150°C (Tj)

Package / Case:

8-SOIC (0.154", 3.90mm Width)

Base Product Number:

FDS89

Manufacturer:

onsemi

Product Status:

Obsolete

Configuration:

2 P-Channel (Dual)

Drain to Source Voltage (Vdss):

20V

Rds On (Max) @ Id, Vgs:

55mOhm @ 4A, 4.5V

Gate Charge (Qg) (Max) @ Vgs:

28nC @ 5V

Power - Max:

900mW

Mounting Type:

Surface Mount

Supplier Device Package:

8-SOIC

Environmental & Export classification

Moisture Sensitivity Level (MSL):

1 (Unlimited)

ECCN:

EAR99

REACH Status:

REACH Unaffected

HTSUS:

8541.21.0095



May 1998

FDS8934A

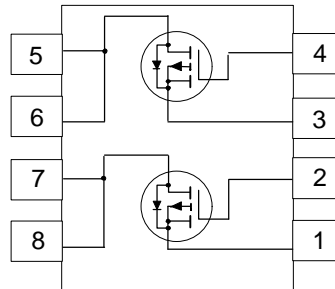
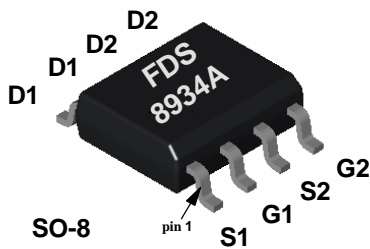
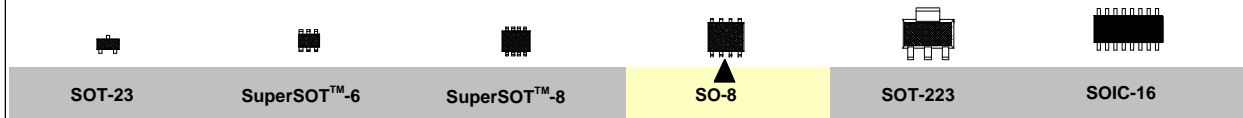
Dual P-Channel Enhancement Mode Field Effect Transistor

General Description

SO-8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- 4 A , -20 V, $R_{DS(ON)} = 0.055 \Omega @ V_{GS} = -4.5 V$,
 $R_{DS(ON)} = 0.072 \Omega @ V_{GS} = -2.5 V$.
- High density cell design for extremely low $R_{DS(ON)}$.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.



Absolute Maximum Ratings $T_A = 25^\circ C$ unless otherwise noted

Symbol	Parameter	FDS8934A	Units
V_{DSS}	Drain-Source Voltage	-20	V
V_{GSS}	Gate-Source Voltage	-8	V
I_D	Drain Current - Continuous (Note 1a)	-4	A
	- Pulsed	-20	
P_D	Power Dissipation for Dual Operation	2	W
	Power Dissipation for Single Operation (Note 1a)	1.6	
	(Note 1b)	1	
	(Note 1c)	0.9	
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 150	$^\circ C$

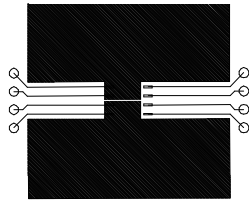
THERMAL CHARACTERISTICS			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	40	$^\circ C/W$

Electrical Characteristics ($T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted)

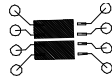
Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$	-20			V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	$I_D = -250\text{ }\mu\text{A}$, Referenced to $25\text{ }^\circ\text{C}$		-23		mV/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16\text{ V}, V_{GS} = 0\text{ V}$			-1	μA
I_{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 8\text{ V}, V_{DS} = 0\text{ V}$			-100	nA
I_{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -8\text{ V}, V_{DS} = 0\text{ V}$			-100	nA
ON CHARACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$	-0.4	-0.6	-1	V
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Temp. Coefficient	$I_D = -250\text{ }\mu\text{A}$, Referenced to $25\text{ }^\circ\text{C}$		4		mV/ $^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = -4.5\text{ V}, I_D = -4\text{ A}$		0.043	0.055	Ω
		$T_J = 125\text{ }^\circ\text{C}$		0.062	0.077	
		$V_{GS} = -2.5\text{ V}, I_D = -3.4\text{ A}$		0.059	0.072	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = -10\text{ V}, V_{DS} = -5\text{ V}$	-20			A
g_{FS}	Forward Transconductance	$V_{DS} = -10\text{ V}, I_D = -4\text{ A}$		13		S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	$V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V}, f = 1.0\text{ MHz}$		1130		pF
C_{oss}	Output Capacitance			480		pF
C_{rss}	Reverse Transfer Capacitance			120		pF
SWITCHING CHARACTERISTICS (Note 2)						
$t_{D(on)}$	Turn - On Delay Time	$V_{DS} = -10\text{ V}, I_D = -1\text{ A}$ $V_{GS} = -4.5\text{ V}, R_{GEN} = 6\text{ }\Omega$		8	16	ns
t_r	Turn - On Rise Time			23	37	
$t_{D(off)}$	Turn - Off Delay Time			260	360	
t_f	Turn - Off Fall Time			90	125	
Q_g	Total Gate Charge	$V_{DS} = -5\text{ V}, I_D = -4\text{ A}, V_{GS} = -5\text{ V}$		20	28	nC
Q_{gs}	Gate-Source Charge			2.8		
Q_{gd}	Gate-Drain Charge			3.2		
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
I_S	Maximum Continuous Drain-Source Diode Forward Current				-1.3	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = -1.3\text{ A}$ (Note 2)		-0.7	-1.2	V

Notes:

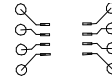
- $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. $78\text{ }^\circ\text{C/W}$ on a 0.5 in^2 pad of 2oz copper.



b. $125\text{ }^\circ\text{C/W}$ on a 0.02 in^2 pad of 2oz copper.



c. $135\text{ }^\circ\text{C/W}$ on a 0.003 in^2 pad of 2oz copper.

Scale 1 : 1 on letter size paper

- Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2.0\%$.

Typical Electrical Characteristics

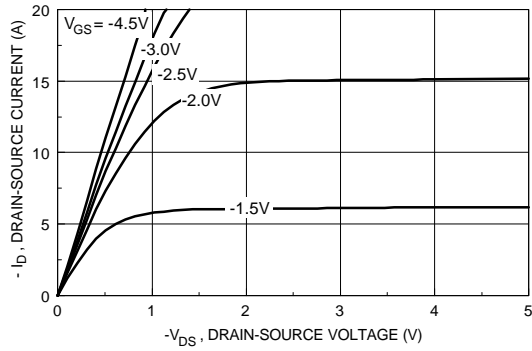


Figure 1. On-Region Characteristics.

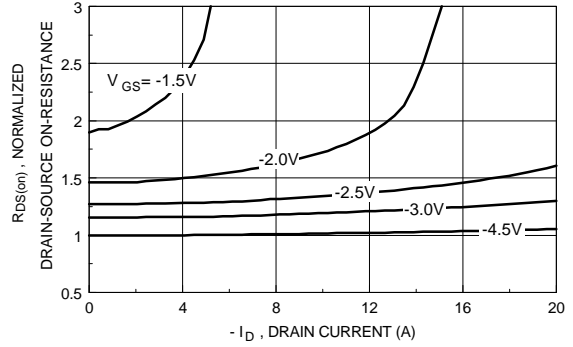


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

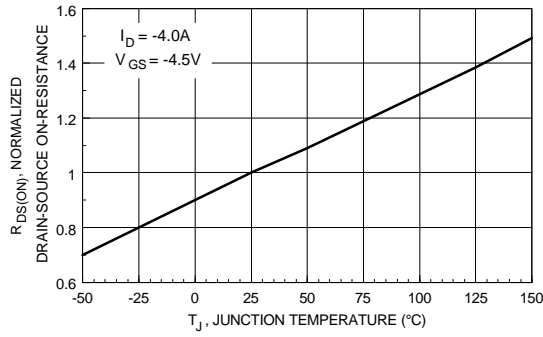


Figure 3. On-Resistance Variation with Temperature.

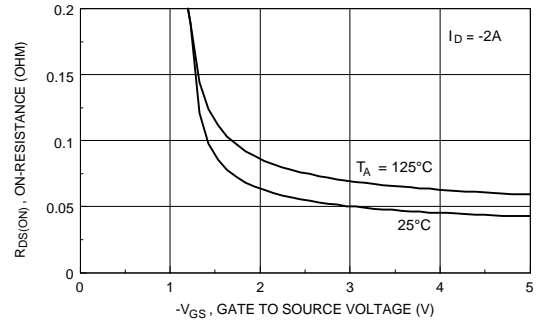


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

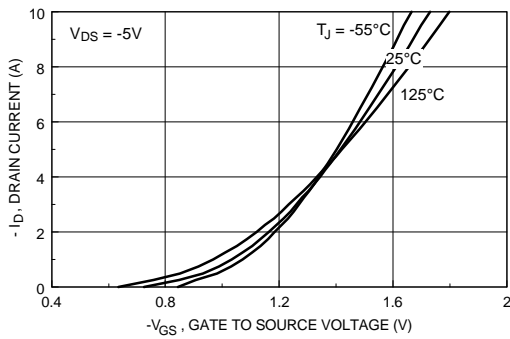


Figure 5. Transfer Characteristics.

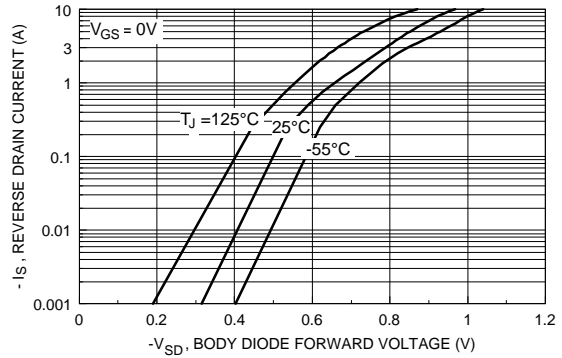


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics (continued)

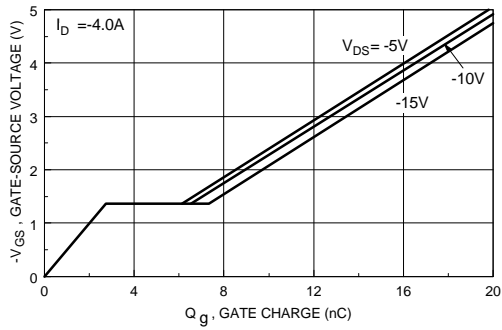


Figure 7. Gate Charge Characteristics.

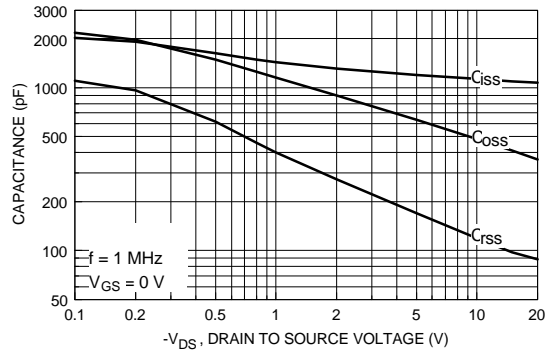


Figure 8. Capacitance Characteristics.

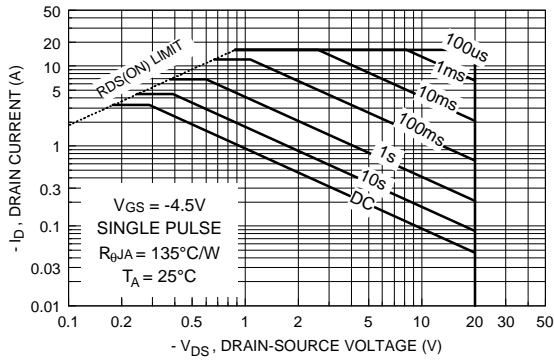


Figure 9. Maximum Safe Operating Area.

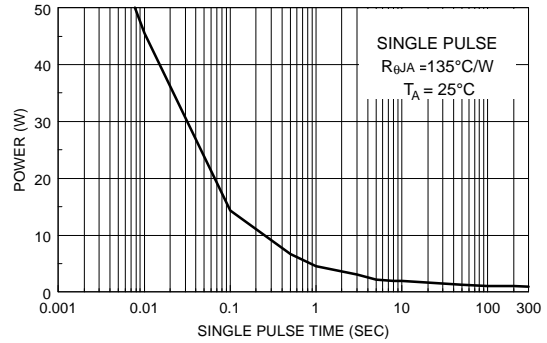


Figure 10. Single Pulse Maximum Power Dissipation.

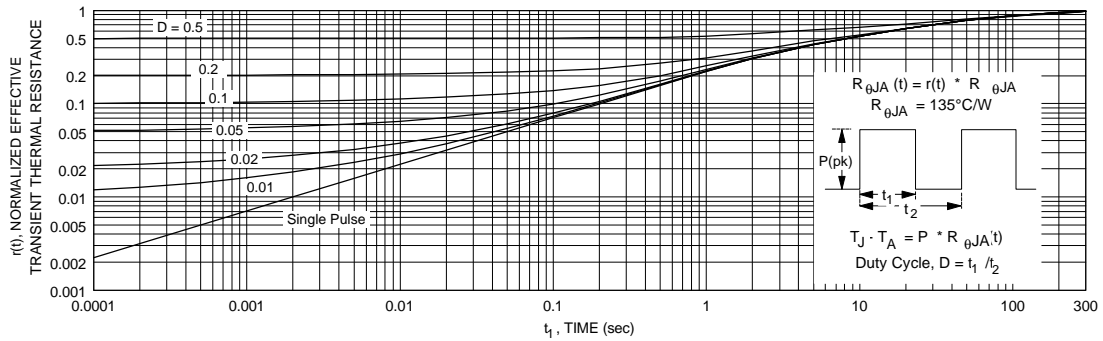


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c.
Transient thermal response will change depending on the circuit board design.

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